Date Created : 2007/11/26 Date Issued On : 2007/11/29 PCN# : Q4074106-A

DESIGN/PROCESS CHANGE NOTIFICATION -- FINAL

This is to inform you that a design and/or process change will be made to the following product(s). This notification is for your information and concurrence.

If you require data or samples to qualify this change, please contact Fairchild Semiconductor within 30 days of receipt of this notification.

Updated process quality documentation, such as FMEAs and Control Plans, are available for viewing upon request.

If you have any questions concerning this change, please contact:

<u>Technical Contact:</u> Name: Hebert, Mark

E-mail: Mark.Hebert@notes.fairchildsemi.com

Phone: 1-207-775-8600

<u>PCN Originator:</u> Name: Frost, Steve

E-mail: Steve.Frost@fairchildsemi.com

Phone: (207) 775-8637

Implementation of change:

Expected 1st Device Shipment Date: 2008/01/24

Earliest Year/Work Week of Changed Product: 0804

Change Type Description: Wafer Diameter

Description of Change (From): Switch products currently manufactured using Fairchild's 6-inch, class 1, fab process in South Portland, ME.

Description of Change (To): Switch product will now be produced on both 6 inch and 8-inch wafer Diameters. Manufacturing will occur in the same 6-inch Class-1 fab currently producing these products. In some cases, new 8 inch equipment will be added to accommodate the 6 to 8 inch processing conversion. Die size, design, geometry, or layout of the affected products remains un-changed. 8-inch products will be fully compliant to all published data sheet specifications and will be completely interchangeable with current 6-inch product. Quality and reliability will remain at the highest standards already demonstrated with Fairchild's existing products.

Reason for Change: Fairchild Semiconductor is adding 8 inch wafer capacity for processing existing switch products currently manufactured using Fairchild's 6-inch, class 1, fab process in South Portland, ME.

Qual/REL Plan Numbers: Q20070399

Qualification:

All environmental & mechanical stresses outlined in reliability qualification plan Q20070399 successfully meet the requirements for release, qualifying South Portland?s 8 inch FS35C32B fab process for switch products.

Results/Discussion

Toot: (Autoplaya)										
Test: (Autoclave)										
Lot O20070300AAACLV			Device ECA22CZAL40V				Failure Code			
		FSA2267AL10X FSA2267AL10X	SA2267AL10X		0/77					
Q20070399ABACLV Q20070399ACACLV	FSA2267AL10X FSA2267AL10X			0/77						
Q20070399ACACLV Q20070399BAACLV	FSA2267AL10X									
Q20070399BAACLV Q20070399BBACLV	FSA2268TUMX			0/77						
Q20070399BCACLV	FSA2268TUMX									
Test: (High Temperature Storage Life)										
Lot Devi				168-HOL	JRS	1000-HOURS	Failure Code			
		A2267AL10X A2267AL10X		0/77		0/77				
				0/77		0/77				
		A2267AL10X		0/11		0/77				
				0/77		0/11				
		A2267AL10X		0,1.1		0/77				
		SA2268TUMX				1				
Q20070399BAHTSL			2268TUMX			0/77				
				0/77						
Q20070399BBHTSL			A2268TUMX			0/77				
Q20070399BCHTSL		A2268TUMX		0/77						
Q20070399BCHTSL	FS	SA2268TUMX				0/77				
Test: (Static Op Life)		-				-	·			
Lot	Device	<u> </u>	168-HOL	JRS	500-HOURS	1000-HOUR	S Failure Code			
Q20070399AASOPL1		67AL10X	0/77							
					0/77					
						0/77				
Q20070399ABSOPL1			0/77							
					0/77					
						0/77				
Q20070399ACSOPL1			0/77		0.777					
			1		0/77	0/77				
0200702000 4 0000 4	EC 4.00	COTLIMY	0/77			0/77				
Q20070399BASOPL1 FSA226		8TUMX 0/77			0/77					
	-		-		0/11	0/77				
Q20070399BBSOPL1			0/77			0/11				
		0,11			0/77					
						0/77				
Q20070399BCSOPL1			0/77							
					0/77					
						0/77				
Test: -65C, 150C (Te	mper	ature Cycle)								
Lot		Device			500-CYCLES	3	Failure Code			
Q20070399AATMCL1		FSA2267AL10X			0/77		-			
Q20070399ABTMCL1		FSA2267AL10X			0/77					
Q20070399ACTMCL1		FSA2267AL10X			0/77					
		FSA2268TUMX	FSA2268TUMX		0/77					
		FSA2268TUMX			0/77					
Q20070399BCTMCL1		FSA2268TUMX			0/77					
Test: 130C (Highly A	cceler	rated Stress Tes	st)				-			
Lot		Device	,		96-HOURS		Failure Code			
		FSA2267AL10X			0/45					
Q20070399ABHAST1		FSA2267AL10X		0/45						
Q20070399ACHAST1		FSA2267AL10X		0/45						
Q20070399BAHAST1		FSA2268TUMX	FSA2268TUMX		0/45					
Q20070399BBHAST1		FSA2268TUMX			0/45					
Q20070399BCHAST1		FSA2268TUMX		0/45						
Test: MSL(1), PKG(S	Small)	PeakTemp(260	CVC). CVC	cles(3)	(Precondit	ion)				
Test: MSL(1), PKG(Small), PeakTemp(260c), Cycles(3) (Precondition) Lot Device Results Failure Code										
Q20070399AAPCNL1A		FSA2267AL10X			0/276					
Q20070399ABPCNL1A		FSA2267AL10X			0/276					
Q20070399ACPCNL1A		FSA2267AL10X			0/276					
Q20070399BAPCNL1A		FSA2268TUMX			0/276					
Q20070399BBPCNL1A		FSA2268TUMX	FSA2268TUMX		0/276					
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Q20070399BCPCNL1A FSA	SA2268TUMX 0	0/276	
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Product Id Description:

Affected FSIDs:

FSA2156L6X	FSA2267AL10X	FSA2267L10X
FSA2268TUMX	FSA2268UMX	FSA2467MPX
FSA2567MPX	FSA5157L6X	FSHDMI04MTDX
FSSD06BQX	FSUSB30BQX	FSUSB30L10X
FSUSB30UMX	FSUSB31L8X	